Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/705,456	CLARK ET AL.
Examiner	Art Unit
Stephen M. D'Agosta	2683

	SEARCHED				
Class	Subclass	Date	Examiner		
455	414.1	f-20-05	AP		
	419				
	420				
	466				
370	338				
709	237				
	217-219				
715	500.1				
	513				
	522				
	523				
	760	+	+		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
INVENTOR SENTERH	f-50-02	70		
EAST DBJ: - US PAT, PERUS, OCPR - EPU, JPO - DERWENT, IBM				
TEXT SEARCH: ATTACHED.				